

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

re application of: Wayne Biao Liu

Attorney Docket No.: DSC1P003

Application No.: 09/938,708

Examiner: Not yet assigned

Filed: August 24, 2001

Group: 2825

Title: SPACE REDUCTION IN

COMPOSITIONAL STATE SYSTEMS

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as First Class Mail to: Commissioner for

Tara Hayden

Patents, Wash gton, DC 20231 on February 20, 2002.

Signed:

INFORMATION DISCLOSURE ST **ATEMENT** 37 CFR §§1.56 AND 1.97(b)

Commissioner for Patents Washington, DC 20231

Dear Sir:

TC. 2800 MAIL ROOM

The references listed in the attached PTO Form 1449, copies of which are attached, may be material to examination of the above-identified patent application. Applicants submit these references in compliance with their duty of disclosure pursuant to 37 CFR §§1.56 and 1.97. The Examiner is requested to make these references of official record in this application.

This Information Disclosure Statement is: (i) filed within three (3) months of the filing date of the above-referenced application, (ii) believed to be filed before the mailing date of a first Office Action on the merits, or (iii) believed to be filed before the mailing of a first Office Action after the filing of a Request for Continued Examination under §1.114. Accordingly, it is believed that no fees are due in connection with the filing of this Information Disclosure Statement. However, if it is determined that any fees are due, the Commissioner is hereby authorized to charge such fees to Deposit Account 500388 (Order No. DSC1P003).

Respectfully submitted,

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Information Disclosure Statement By Applicant

(Use Several Sheets if Necessary)

Atty Docket No. DSC1P003

xet No. Application No.: 09/938,708

Applicant:

Wayne Biao Liu

Filing Date August 24, 2001 Group 2825

U.S. Patent Documents

Exami	ner						Sub-	Filing
Initial		No.	Patent No.	Date	Patentee	Class	class	Date

Foreign Patent or Published Foreign Patent Application

Examiner		Document	Publication	Country or		Sub-	Trans	slation
Initial	No.	No.	Date	Patent Office	Class	class	Yes	No
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Examiner	-		Date Considered					

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.